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# Charon Overview



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# Staffing and Funding

## ➤ Personnel

● 1355

- Larry Musson
- Gary Hennigan
- Suzey Gao
- Mihai Negoita
- Andy Huang
- Jason Gates
- Joe Castro

## ➤ Funding

- ASC/IC
- ASC/P&EM
- ASC/V&V

# What is Charon?

- Semiconductor *TCAD* code with support for modeling displacement damage due to neutron radiation as well as effects from other sources of radiation (e.g. ionization)
- Finite-volume and finite-element discretizations of governing PDEs
  - Drift-Diffusion
  - Drift-Diffusion + Energy (Lattice Heating)

**Electric Potential**  $\left\{ \begin{array}{l} \nabla \cdot (\epsilon \vec{\mathbf{E}}) = q(p - n + C) \\ \vec{\mathbf{E}} = -\nabla V \end{array} \right.$

$\left. \begin{array}{l} \vec{\mathbf{J}}_n = q(n\mu_n \vec{\mathbf{E}} + D_n \nabla n) \\ \vec{\mathbf{J}}_p = q(p\mu_p \vec{\mathbf{E}} - D_p \nabla p) \end{array} \right\}$  **Constitutive Relations**

$\left. \begin{array}{l} \nabla \cdot \vec{\mathbf{J}}_n - qR = q \frac{\partial n}{\partial t} \\ -\nabla \cdot \vec{\mathbf{J}}_p - qR = q \frac{\partial p}{\partial t} \end{array} \right\}$  **Conservation**

$\nabla \cdot (\kappa \nabla T_L) + H = \rho c \frac{\partial T_L}{\partial T}$  **Lattice Heating**

# Unique Capabilities Provided by Charon

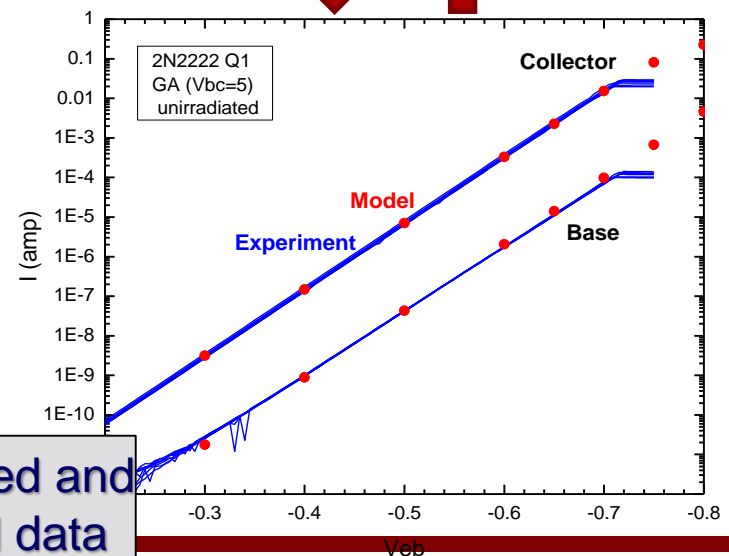
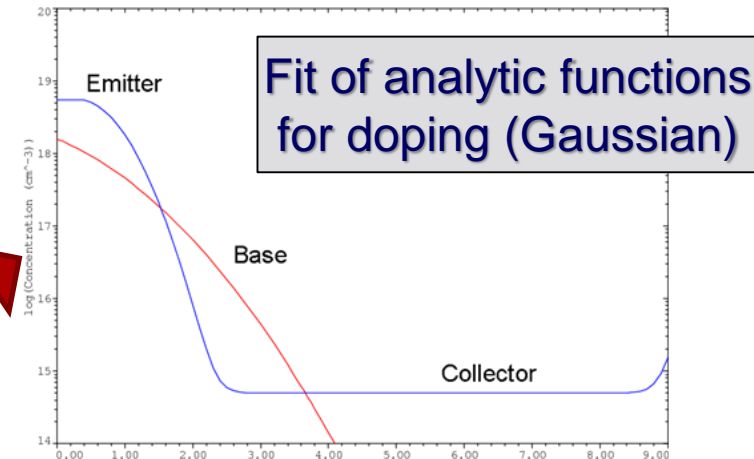
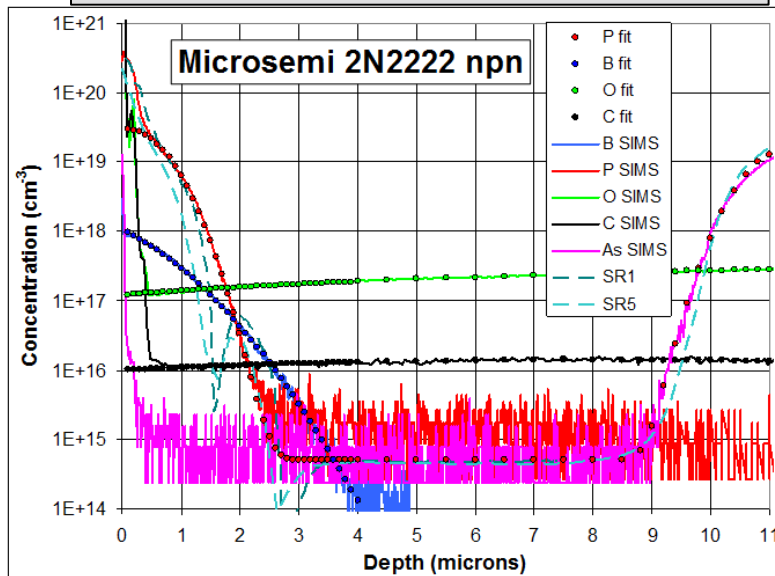
- Two & three dimensional + parallel capability
- Production quality code using current best practices for software development
  - Adheres to formal SQE practices
    - Monitored with periodic audits
  - Utilizes rigorous verification
    - MMS (Method of Manufactured Solutions)
    - Automated regression testing (nightly/weekly)
- Utilizes latest solver technology
  - Via solvers in Sandia's Trilinos toolkit
- Incorporates empirical (fast running) and high fidelity physics models for displacement damage

# Environments & Device Modeling Capability

- Environments
  - Normal
  - Dose Rate – reactor environments
  - Total Dose – not validated
  - SEE – Some early, limited capability
- Devices
  - Diodes
  - BJT (Si)
  - HBT (III-V)
  - FETs
  - Memristor
  - Ultra-Wide Band Gap Diodes (new models)

# Normal Environment Characterization (COTS BJT Example)

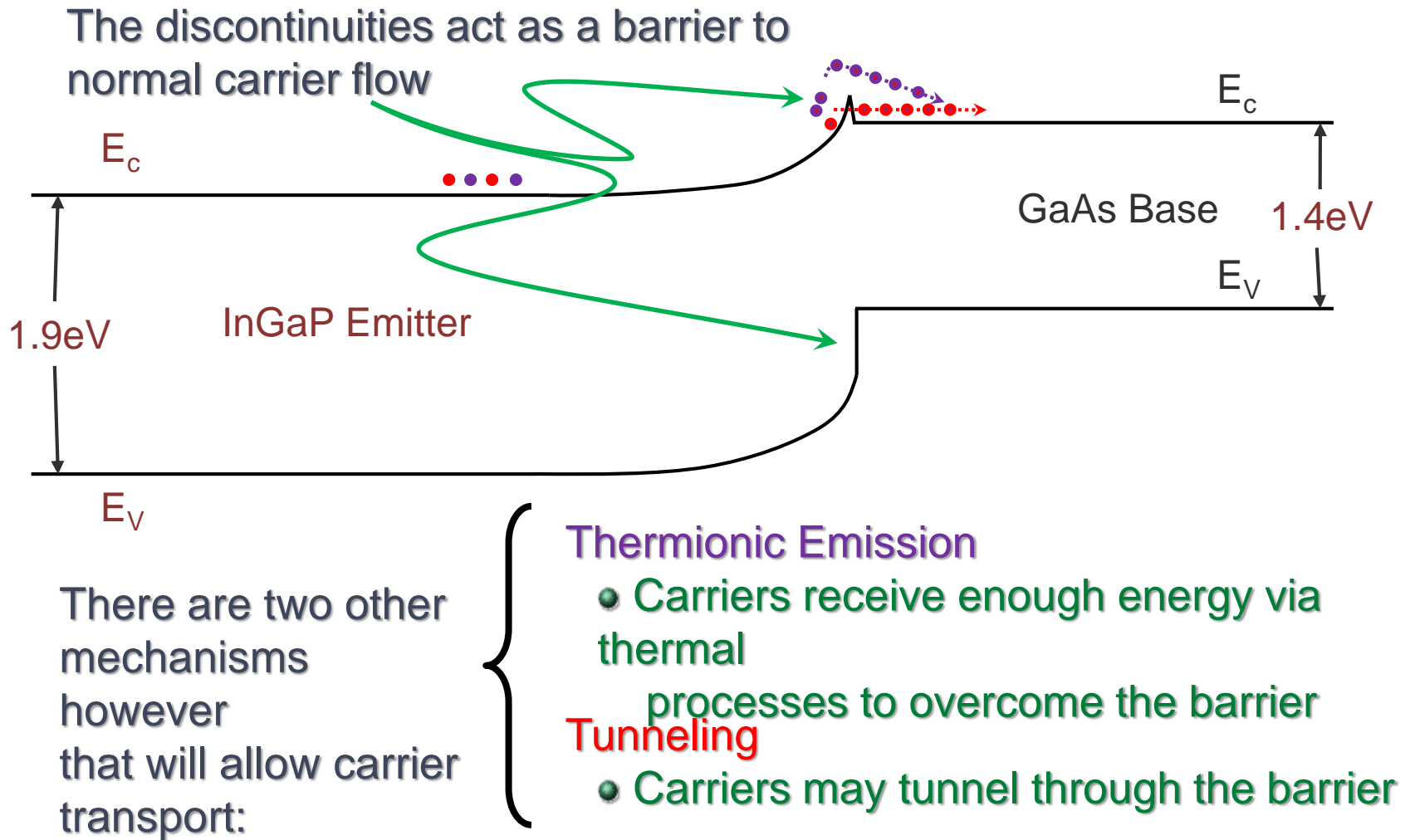
SIMS and SR dopant and impurity  
concentration measurements



Comparison of computed and  
experimental Gummel data



# Bandgap in a $Np^+$ Heterojunction



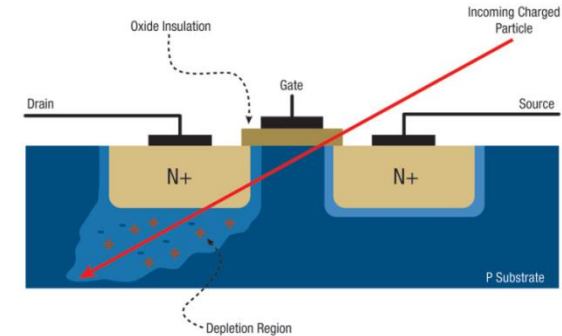
# Capabilities Added to Charon to Support HBT Modeling

- Fermi-Dirac Statistics (highly doped)
- III-V Material Models
- Thermionic Emission
- Tunneling
- Recombination Terms
  - Direct
  - Auger
- Discontinuity of Concentrations at Heterojunction

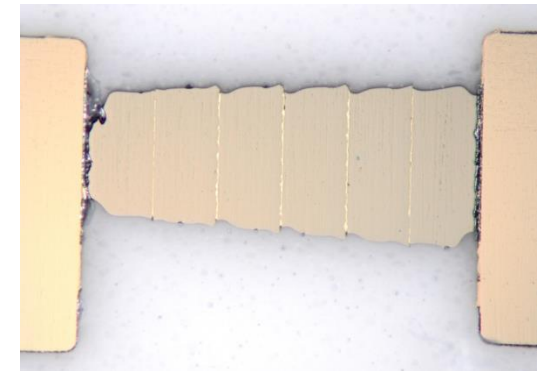


# Ongoing/Future Charon Development

- Expanding Physics Capability
  - SEE/SEU
    - Simple linear charge input available
  - Si HVD Analysis
  - GaN development
    - High Voltage Diodes (support of UWBG GC)
    - HEMTs
  - Frequency Domain Modeling (HB)
    - Both linear and non-linear
  - Improved coupled electrical & thermal- Next Generation Development
  - In preparation of next gen computational Hardware



Single-Event  
Effects



Cross section photo of  
High Voltage Diode  
(HVD)

# Progression of Charon Capabilities

III-V Work

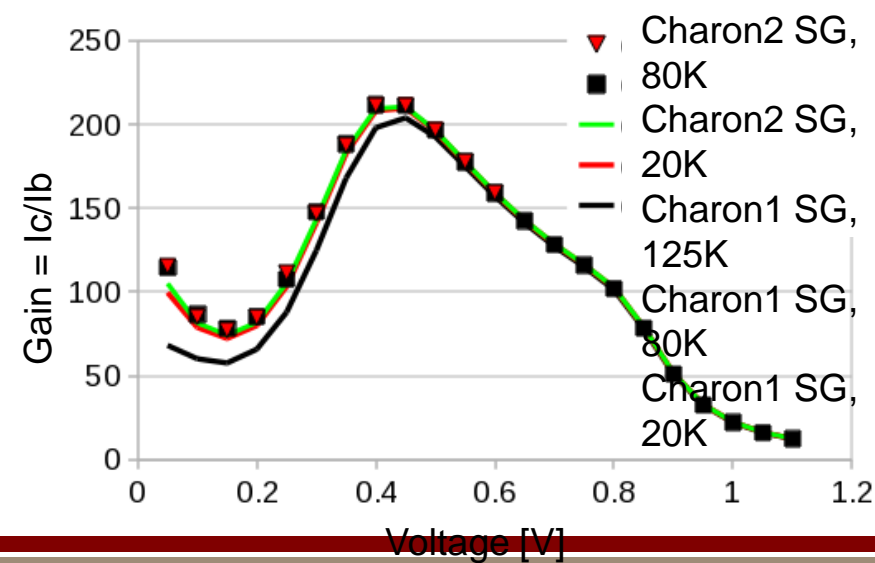
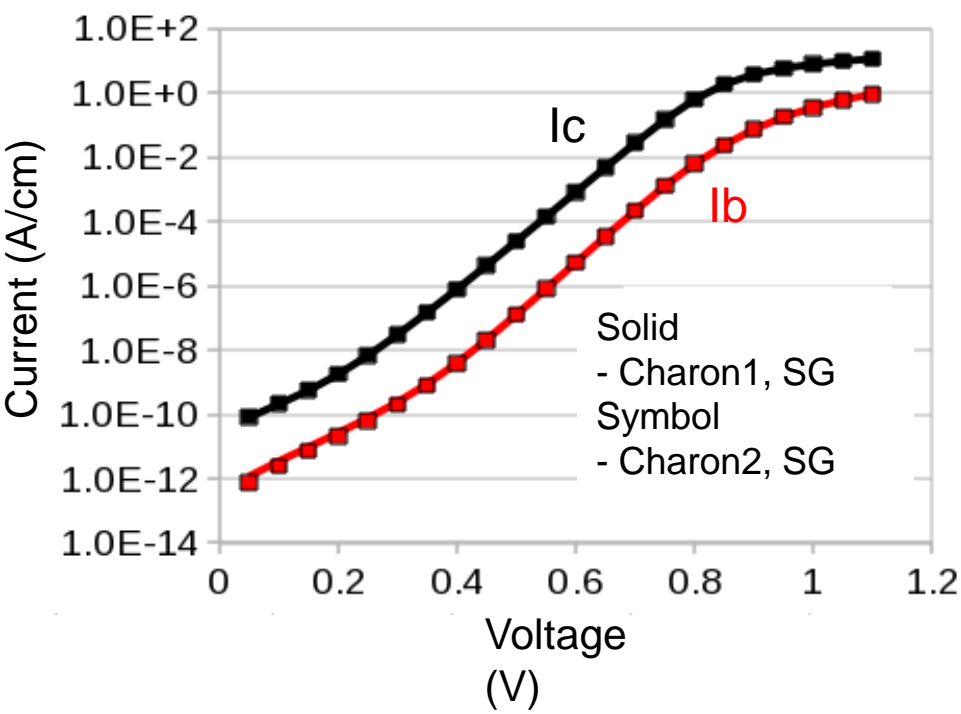
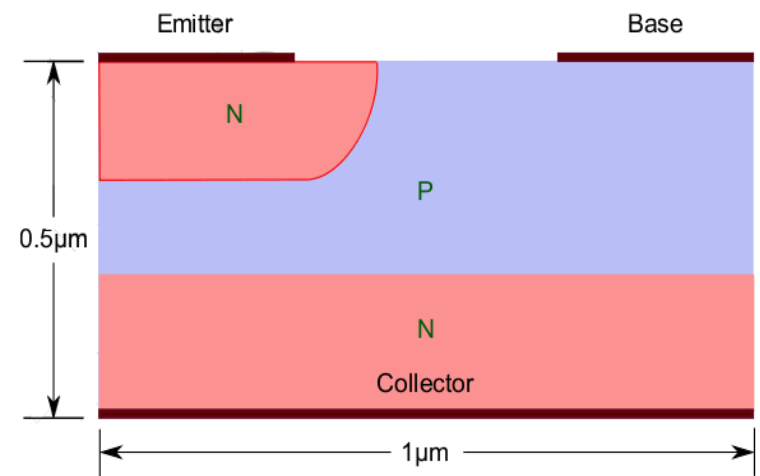
Normal Environment PnP HBT  
2D Modeling of HBTs  
Single Event Effect Modeling  
Cluster Damage Model for GaAs in HBTs  
Cluster Damage Model for Si  
Empirical Damage Model for HBTs  
Normal Environment Npn HBT

Time

FET models with multi-region support  
QASPR Circuit Prototype  
(Silicon BJTs, Mixed-mode)  
QASPR Device Prototype  
(Silicon NPN BJTs)  
PN Diodes  
Research Code (CSRF & LDRD)

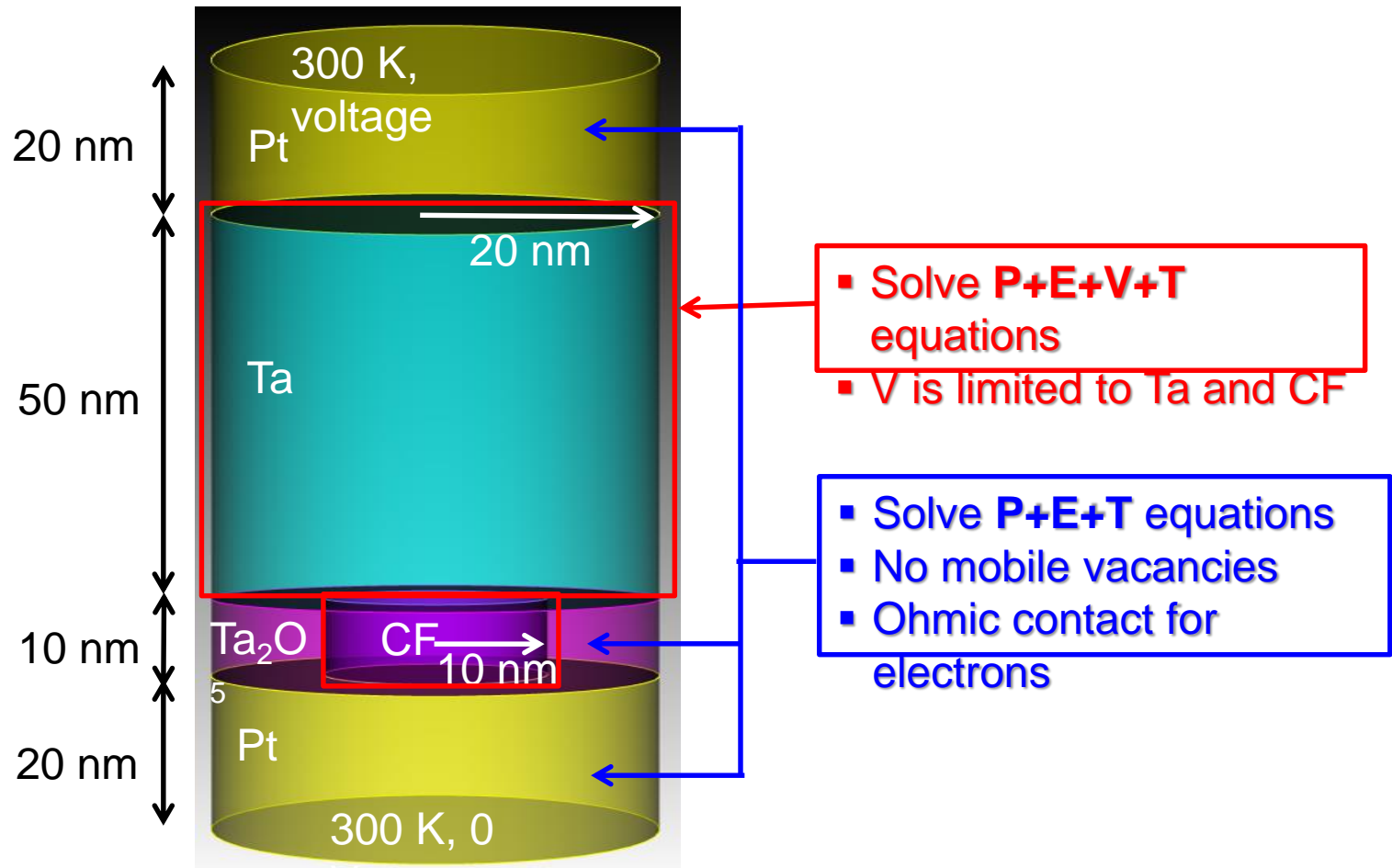
Silicon Work

# Code Verification



Charon1 SG shows strong mesh dependence of the gain when going from 20K to 80K quad elements, while Charon2 SG shows mesh convergence even for 20K elements !

# TaOx Memristor Device Structure



Patrick R. Mickel et al., A physical model of switching dynamics in tantalum oxide memristive devices, APL **102**, 223502 (2013).

# Charon Limitations

- Not a commercial code
- Limited documentation
- Generally requires developer help
  - Non-intuitive input deck
    - A python interface is currently under development
- Different workflow from commercial codes
  - Cubit
  - Non-sequential input

# Charon Availability

- No restrictions for Sandians
- Charon is categorized as an ITAR/Export Control Simulator
  - We have a Government Use Notice (GUN) in place with AWE
  - GUN provides a U.S. government agency or contractor access to software limited to government use
- Open-Source may be a future path
  - Currently in review